

EMB-CV2

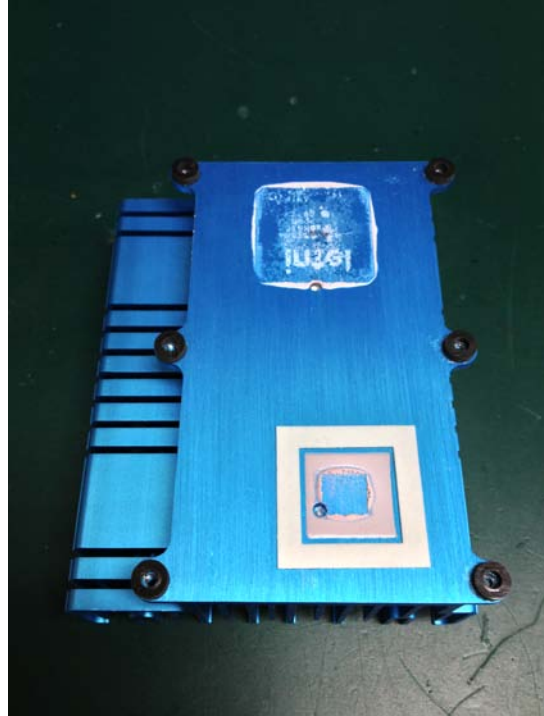
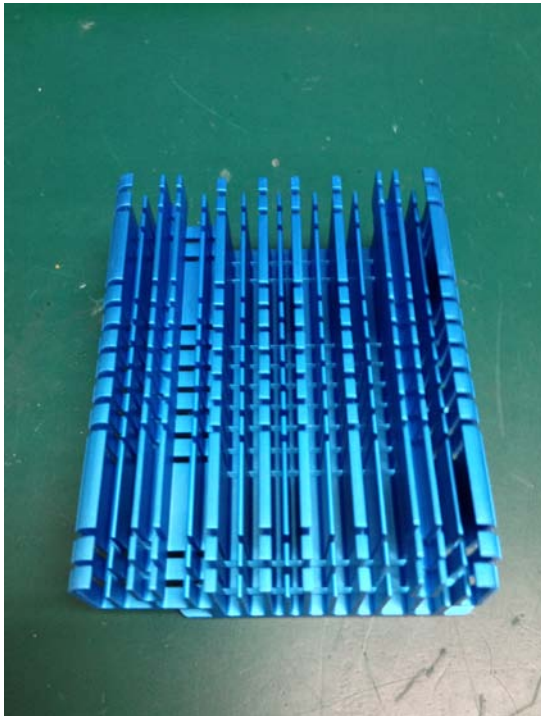
Thermal Image Analysis Report

Summary	<input checked="" type="checkbox"/> Pass <input type="checkbox"/> Fail <input type="checkbox"/> Pass with Deviation Comment: _____				
	Test Result Summary				
	Critical	Major	Minor	Enhancement	
Defect Found	0	0	0	0	
Defect Unsolved	0	0	0	0	

Issue date	Approval	Test Engineer
2013 / 07 / 26	Tom Lin	Jerry Chen

Sample Configuration & Quantity Under Test

- Model name : EMB-CV2 A0.4
- CPU Board : EMB-CV2 A0.4
- CPU : Intel D2550 / 1.86GHz
- Memory : Transcend 2GB * 2 / DDR3 1066 / SEC BCH0-K4B1G0846G
- 3.5" SATA HDD : HITACHI HDS721050CLA362 / 500GB
- BIOS : ECV2AT09
- Test Software : Windows 7 / Run PassMark Burn In Test 7.0 Pro
- Power : AT Power
- Heat Sink :



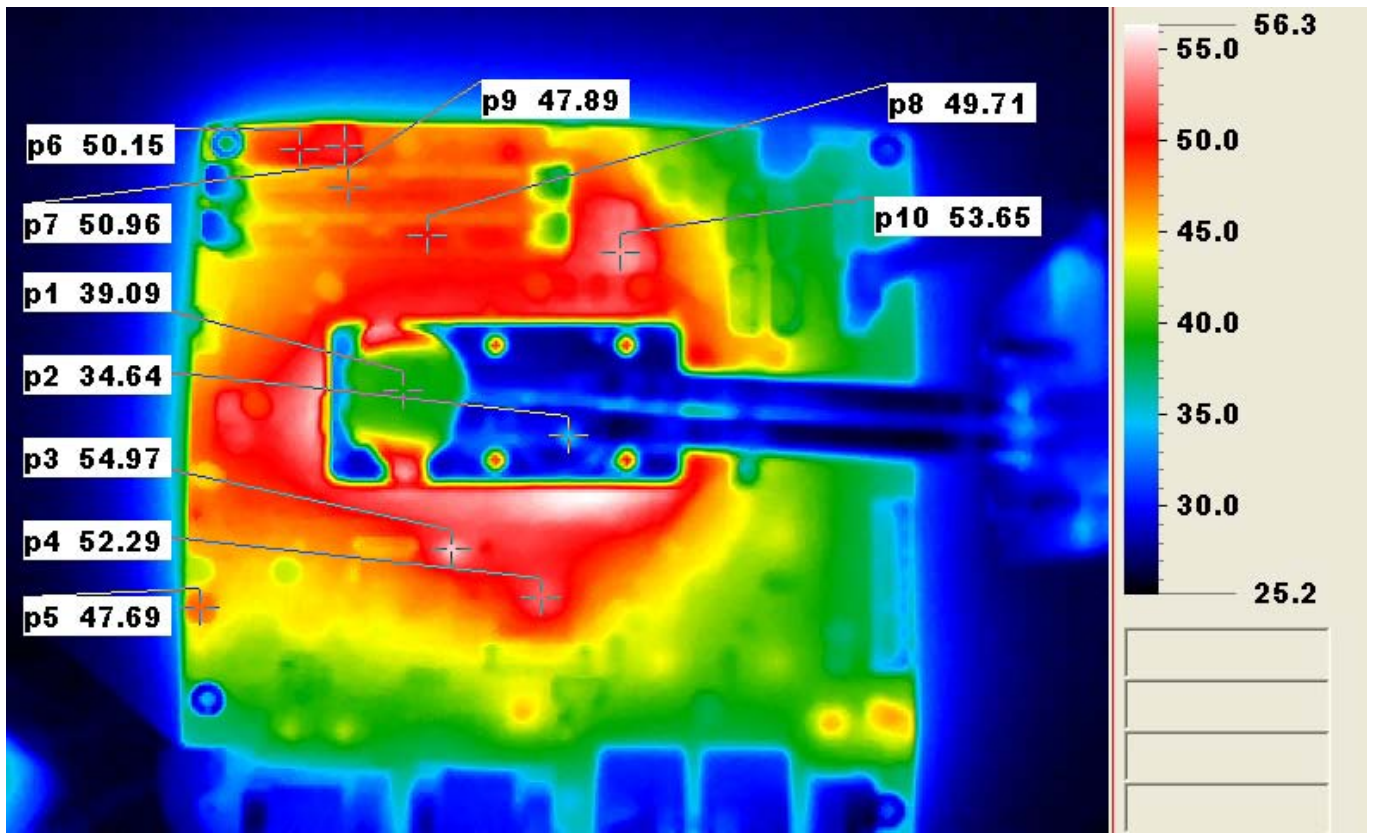
Thermal Image Analysis

1. Test Date: 2013-07-25
2. Test Product: EMB-CV2 A0.4
3. Test Site: AAEON QE Dept.
4. Temperature Measurement:
 - 4.1. 40 Channel Thermal Recorder:
 - 4.1.1 YOKOGAWA Inc,
 - 4.2.2 Model: DA100-13-1D
Date of Calibration: 2012/10/08
Serial Number: 12A323190
 - 4.2. IR Scanner: Infrared Camera
 - 4.2.1 NEC Avio Infrared Technologies Co., Ltd.
 - 4.2.2 Model: Thermo GEAR G100W2-D
Date of Calibration: 2013/01/08
Serial Number: 1051444
5. Test Condition:

Test by DA-100: 24.9°C with Heat Sink
6. Take Picture Time:

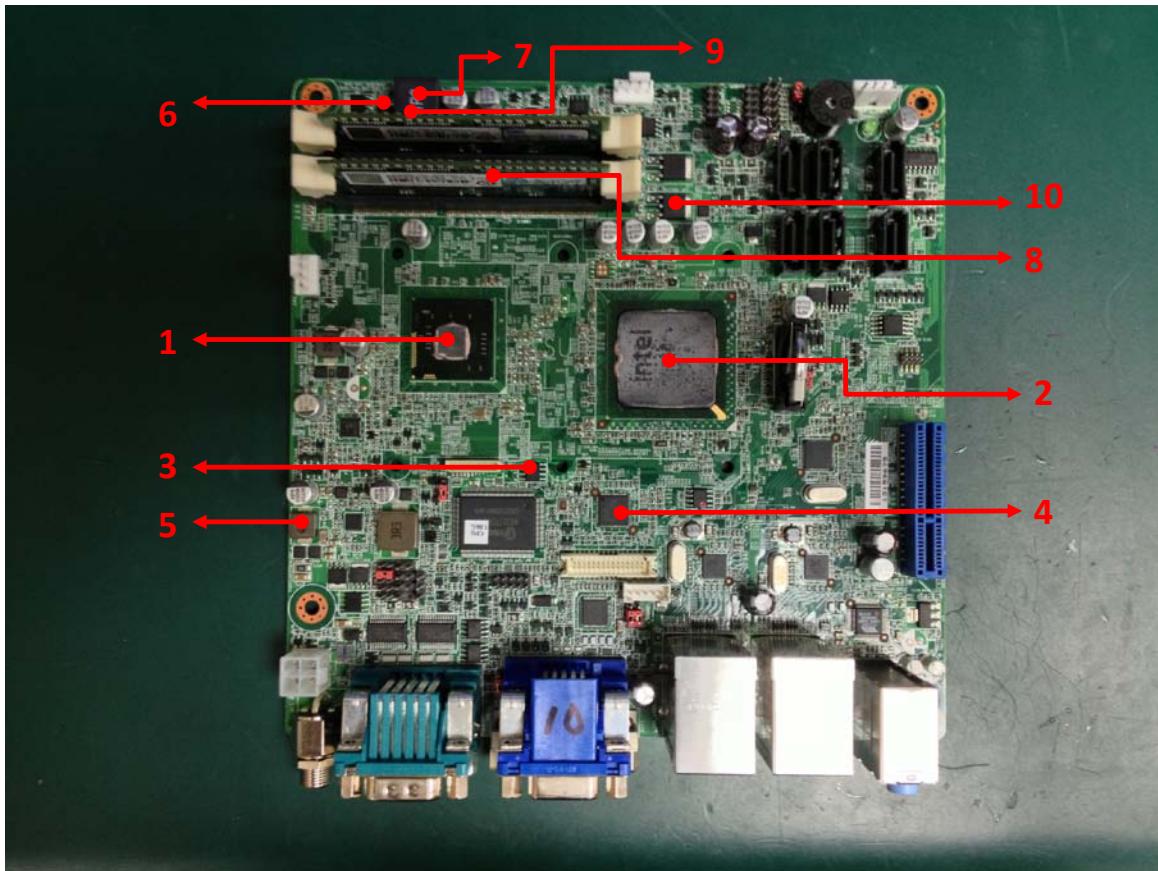
After power on 2 hours

Temperature Profile Test:
Component Side:



Terminal Recorder:

Measuring Thermal Couple Position :



Using YOKOGAWA / DARWIN DA100-100-13-1D test

Point	Position	Describe	Tc (*1) (°C)	Tm (*2) Measured Under		Note
				24.9°C	60°C	
1	U11	(TF)INTEL CPU.Cedarview.1.86GHz.D2550	100	53.3	88.4	
2	U12	(TF) Chipset.AF82801.INTEL.ICH10R	109	47.7	82.8	
3	U18	(TF)REG.Low-Voltage LDO Regulator.UPI.UP0104PSU8	125	53.3	88.4	
4	U22	(TF)DisplayPort to LVDS Converter.Chrontel.CH7511B-BF	125	49.6	84.7	
5	L7	(TF)COIL.4.7uH.20%,GOTREND.GSTD6030PE-4R7M	125	47.1	82.2	
6	Q8	(TF)PWR. N-MOSFET. NXP.PH7030AL	100	45.5	80.6	
7	L1	(TF)INDUCTOR. CHUNG SHUO.CS1112-1R2-I43U	125	45.9	81	
8		Memory chipset - 1	95	43.9	79	

9		Memory chipset - 2	95	43.1	78.2	
10	Q26	(TF)PWR. N-Channel MOSFET.NIKO-SEM.P0903BDL	125	48.5	83.6	

Note(*):
 1. "Tc" indicates the component's case maximum temperature value specified in its datasheet.
 2. "Tm" indicates the measured Tc value under working environmental temperature within product specification.
 3. **Judgment Criteria:**
 - **Fail** : $T_m > T_c + 5^{\circ}\text{C}$; The measured value is over specification plus margin.
 - **Margin** : $T_c + 5^{\circ}\text{C} > T_m > T_c - 10^{\circ}\text{C}$; The measured value is within specification with margin.
 For FANLESS system application, it is strongly recommended to add thermal dissipation design for better reliability.
 - **Pass** : $T_m < T_c - 10^{\circ}\text{C}$; The measured value is with safety margin.
 4. **Defect NO.**